

Tin Whisker Monitor Report

SUBCON	ISPL	
COVERAGE	2007 QTR 1	
DEVICE	MAX809TEUR-T	SOT23-3L
	MAX6412UK29+T	SOT23-5L
	MAX8867E2R25+T	TSOT23-5L
	MAX6510HAUT-T	SOT23-6L
DATE SAMPLED	18 JAN, 2007	

I. PLATING WORKMANSHIP SUMMARY

PLATING CHEMISTRY	NFEP TECHNIC
FINISH	MATTE
PLATING THICKNESS	550 micro inch

II. WHISKER TEST SUMMARY

TEST	READOUT1		READOUT2		READOUT3	
RTS 30°C / 60%RH	1000 H (MAR 29)		2000 H (MAY 10)		3000H (JUNE 21)	
MAX809TEUR-T	0 / 5	0 growth	0 / 5	< 5 um	0 / 5	< 5 um
MAX6412UK29+T	0 / 5	0 growth	0 / 5	< 5 um	0 / 5	< 5 um
MAX8867E2R25+T	0 / 5	0 growth	0 / 5	< 5 um	0 / 5	< 5 um
MAX6510HAUT-T	0 / 5	0 growth	0 / 5	< 5 um	0 / 5	< 5 um
T/HS 60°C / 85%RH	1000 H (MAR 29)		2000 H (MAY 10)		3000H (JUNE 21)	
MAX809TEUR-T	0 / 5	0 growth	0 / 5	< 5 um	0 / 5	< 5 um
MAX6412UK29+T	0 / 5	0 growth	0 / 5	< 5 um	0 / 5	< 5 um
MAX8867E2R25+T	0 / 5	0 growth	0 / 5	< 5 um	0 / 5	< 5 um
MAX6510HAUT-T	0 / 5	0 growth	0 / 5	< 5 um	0 / 5	< 5 um
TC 85°C / -55°C	500 C *		1000 C		1500 C	
MAX809TEUR-T						
MAX6412UK29+T						
MAX8867E2R25+T						
MAX6510HAUT-T						

* EQUIPMENT BREAKDOWN FEB17 2007. SUSPENDED UNTIL FURTHER NOTICE.

III. METHODOLOGY

INSPECTION METHOD : 100X MAGNIFICATION, NO LESS THAN 6 LEADS PER PACKAGE

SAMPLING FREQUENCY : 1 LOT / 3 MONTHS

SAMPLE SIZE : 5 UNITS PER TEST CONDITION

FAILURE CRITERIA : > 40 μm